



# BEAM LOSS MONITORS DEPENDABILITY

#### STATE OF ART



# **Basic Concepts**



## System fault events

- \*BLM are designed to prevent the Magnet Disruption (MaDi) due to an high loss (~30 downtime days).
- \*BLM should avoid false dumps (FaDu) (~6 downtime hours).
- \*\* Use of Safety Integrity Level (SIL), IEC 61508.



# Sil Approach 1/4



# Event likelihood (both)

Category	Description	Indicative frequency level (per year)
Frequent	Events which are very likely to occur	> 1
Probable	Events that are likely to occur	10 <sup>-1</sup> - 1
Occasional	Events which are possible and expected to occur	10 <sup>-2</sup> - 10 <sup>-1</sup>
Remote	Events which are possible but not expected to occur	10 <sup>-3</sup> - 10 <sup>-2</sup>
Improbable	Events which are unlikely to occur	10 <sup>-4</sup> - 10 <sup>-3</sup>
Negligible / Not credible	Events which are extremely unlikely to occur	< 10 <sup>-4</sup>

MaDi: 100 destructive losses/year



# Sil Approach 2/4



## Consequences

Category	Injury to personnel		Damage to equipment		
	Criteria	N. fatalities (indicative)	CHF Loss	Downtime	
Catastrophic	Events capable of resulting in one or more fatalities	≥1	> 5*10 <sup>7</sup>	> 6 months	
Major	Events capable of resulting in very serious injuries	0.1 (or 1 over 10 accidents)	10 <sup>6</sup> - 5*10 <sup>7</sup>	20 days to 6 months	) <u>MaDi</u>
Severe	Events which may lead to serious injuries	0.01 (or 1 over 100 accidents)	10 <sup>5</sup> - 10 <sup>6</sup>	3 to 20 days	
Minor	Events which may lead to minor injuries	0.001 (or 1 over 1000 accidents)	0 - 10 <sup>5</sup>	< 3 days	) <u>FaDu</u>



# Sil Approach 3/4



#### SILs

Event Likelihood	<u>Mal</u>	<u>J1</u> Conse	quence <u>Fa</u>	<u>Du</u>
	Catastrophic	Major	Severe	Minor
Frequent	SIL 4	SIL 3	SIL 3	SIL 2
Probable	SIL 3	SIL 3	SIL 3	SIL 2
Occasional	SIL 3	SIL 3	SIL 2	SIL 1
Remote	SIL 3	SIL 2	SIL 2	SIL 1
Improbable	SIL 3	SIL 2	SIL 1	SIL 1
Negligible / Not Credible	SIL 2	SIL 1	SIL 1	SIL 1



# Sil Approach 4/4



# Failure probability

Low demand mode of Operation ( <1 year)

High demand / continuous mode of operation

SIL	Average probability of failure to perform its design function on demand (FPPD <sub>ave</sub> )		
4	$10^{-5} < Pr < 10^{-4}$		
3	$10^{-4} < Pr < 10^{-3}$		
2	$10^{-3} < Pr < 10^{-2}$		
1	$10^{-2} < Pr < 10^{-1}$		

SIL	Probability of a dangerous failure per hour
4	$10^{-9} < Pr < 10^{-8}$
3	$10^{-8} < Pr < 10^{-7}$
2	$10^{-7} < Pr < 10^{-6}$
1	$10^{-6} < Pr < 10^{-5}$



# Our Scenario

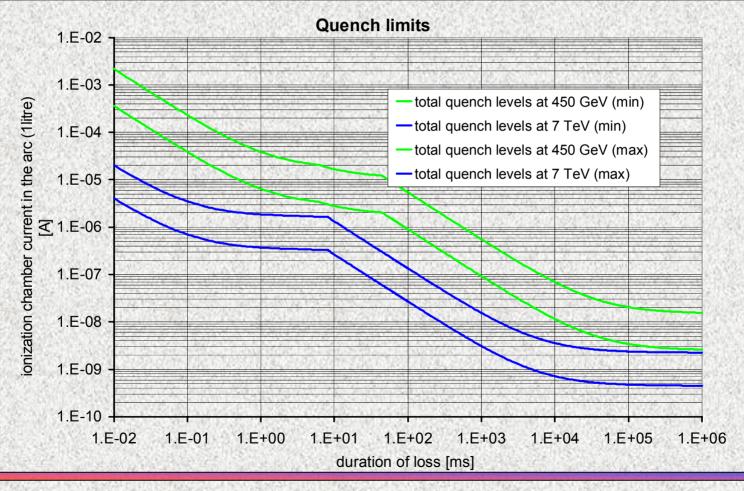


- ★ ~180 BLMs for collimators.
- \* Scan every 40 μs.
- ★ Check every 1 ms.
- \* Signal with 8 order of magnitude.



# Threshold Levels







# Our Selection

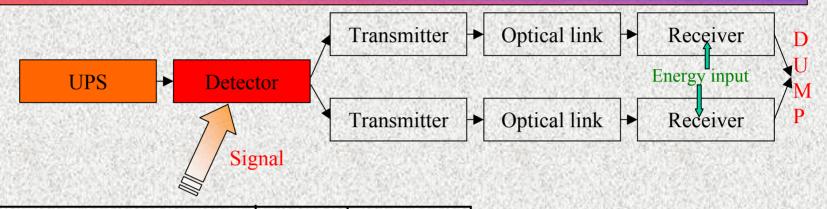


- \* Ionization chambers: reliable (no fails with 200 chamber during 20 years in SPS), wide range.
- \* Current to Frequent Converter (CFC), from 10<sup>-2</sup> to 5 10<sup>6</sup> Hz.
- \* Two optical lines: bandwidth, reliability.
- \* Use FPGAs: reliability, flexibility, cheap.



# Our Layout



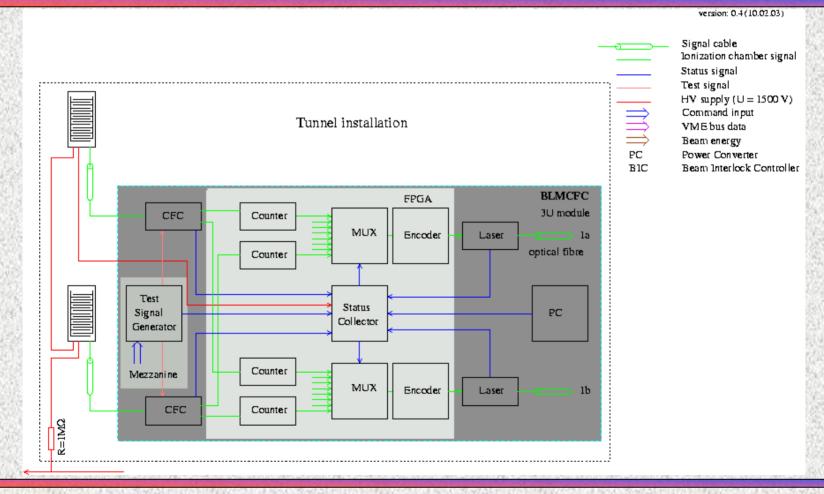


ELEMENT	λ [1/h]	inspection [h]
Ionization Chamber + 400m cable	2.58E-08	20
Amplifier (CFC)	2.78E-08	20
Photodiode	3.18E-08	2.78E-07
Switch (CFC)	8.70E-08	20
2 Optical connectors	2.00E-07	2.78E-07
Optical fiber	2.00E-07	2.78E-07
FPGA RX	6.99E-07	2.78E-07
UPS ??	1.00E-06	2.78E-07
FPGA TX	2.02E-06	2.78E-07
Laser	8.46E-06	2.78E-07



# Front-end Electronic

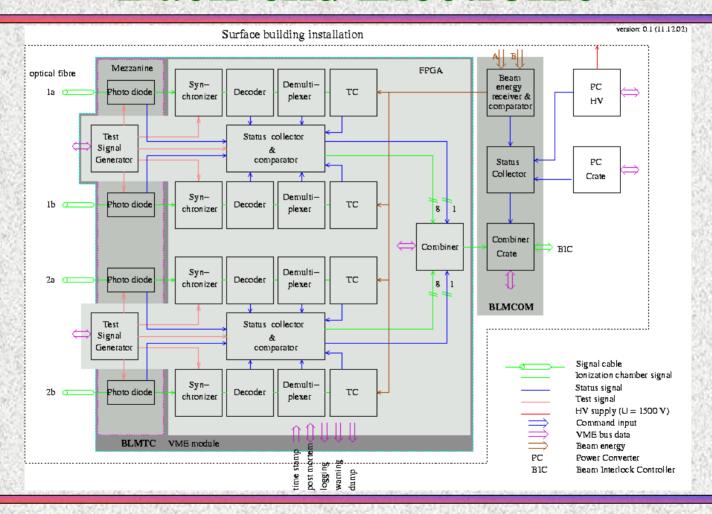






## Back-end Electronic

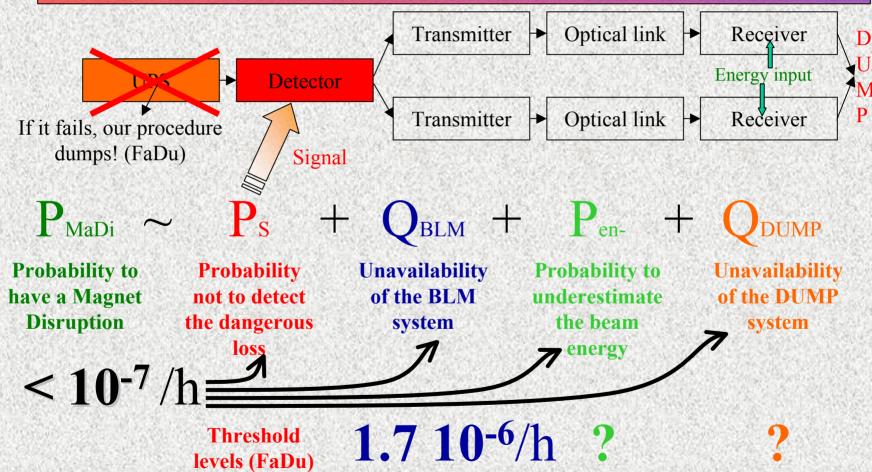






### MaDi 1/2

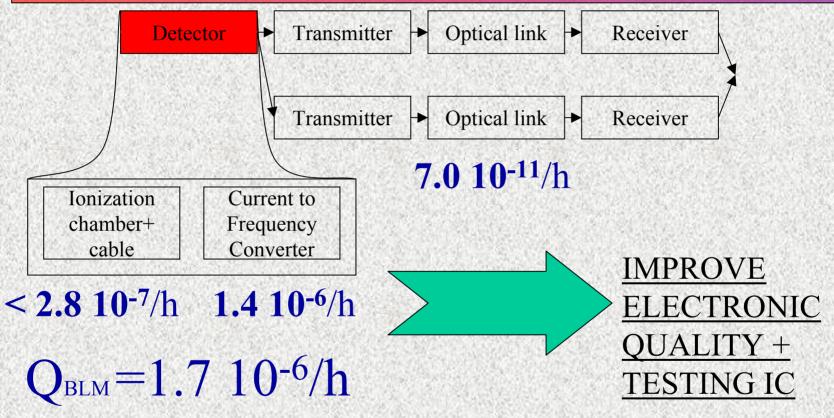






#### MaDi 2/2

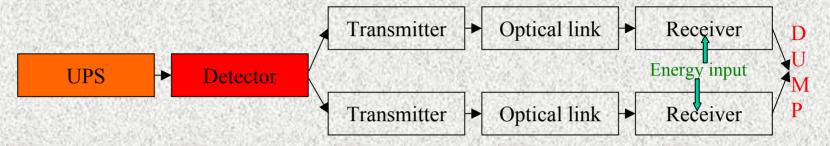


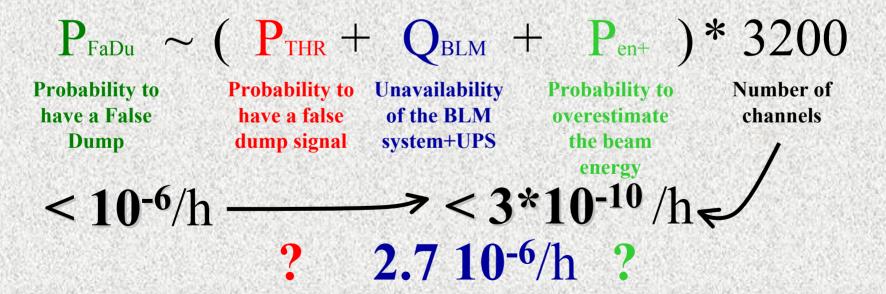




### FaDu









## Risk Matrix 1/2



#### \*(Raw) Foreseen failure rate:

 $\square$  MaDi: 1.7 10-6/h \* 4000 h/y \* 100 = 0.7/y

**Probable** 

Dangerous losses

Beam hours: 200 d\*20 h/d

per years

□FaDu: 2.7 10-6/h \* 4000 h/y \* 3200= 35/y

**Frequent** 

Number of channels



## Risk Matrix 2/2



Frequency		MaDi Consequence FaDu		
	Catastrophic	Major	Severe	Minor
Frequent	I	I	I	II
Probable	I	I	II	III
Occasional	I	II	III	III
Remote	II	II		börder
Improbable	II	ard"hel	опи п	IV
Negligible / Not Credible	mye.	are bey	IV	IV

- I. Intolerable.
- II. Tolerable if risk reduction is impracticable or if costs are disproportionate.
- III. Tolerable if risk reduction cost exceeds improvement.
- IV. Acceptable.



#### Actions



- 1. Improve the Current to Frequency Converter electronic quality.
- 2. Procedure to test the Ionization Chamber as frequent as possible.
- 3. Collect data about current unavailability of Beam Energy System and Beam Interlock Controller.
- 4. Estimation of the threshold levels failure rate for FaDu.
- 5. Multiple detections? If yes: coincidence (es: 2001000) in the Beam Interlock Controller?